

IRF9220/9221/9222/9223  
 IRFP9220/9221/9222/9223  
 IRF9620/9621/9622/9623

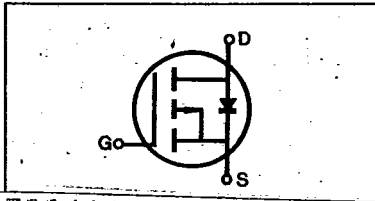
7964142 0005414 B

**P-CHANNEL  
 POWER MOSFETS**

Preliminary Specification SAMSUNG SEMICONDUCTOR INC 98 DE 7964142 0005414 B

-200 Volt, 1.5 Ohm SFET

**PRODUCT SUMMARY**



Part Number	V <sub>DS</sub>	R <sub>DS(on)</sub>	I <sub>D</sub>
IRF/IRFP9220, IRF9620	-200V	1.5Ω	-3.5A
IRF/IRFP9221, IRF9621	-150V	1.5Ω	-3.5A
IRF/IRFP9222, IRF9622	-200V	2.4Ω	-3.0A
IRF/IRFP9223, IRF9623	-150V	2.4Ω	-3.0A

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**FEATURES**

- Low R<sub>DS(on)</sub>
- Improved inductive ruggedness
- Fast switching times
- Rugged polysilicon gate cell structure
- Low input capacitance
- Extended safe operating area
- Improved high temperature reliability

**PACKAGE STYLE**

Package Type	Part Number
TO-3	IRF9220/9221/9222/9223
TO-3P	IRFP9220/9221/9222/9223
TO-220	IRF9620/9621/9622/9623

**MAXIMUM RATINGS**

Characteristic	Symbol	IRF/IRFP				Unit
		9220 9620	9221 9621	9222 9622	9223 9623	
Drain-Source Voltage (1)	V <sub>DSS</sub>	-200	-150	-200	-150	V <sub>dc</sub>
Drain-Gate Voltage (R <sub>GS</sub> =1.0MΩ) (1)	V <sub>DGR</sub>	-200	-150	-200	-150	V <sub>dc</sub>
Gate-Source Voltage	V <sub>GS</sub>	±20				V <sub>dc</sub>
Continuous Drain Current T <sub>C</sub> =25°C	I <sub>D</sub>	-3.5	-3.5	-3.0	-3.0	A <sub>dc</sub>
Continuous Drain Current T <sub>C</sub> =100°C	I <sub>D</sub>	-2.0	-2.0	-1.5	-1.5	A <sub>dc</sub>
Drain Current—Pulsed (3)	I <sub>DM</sub>	-14	-14	-12	-12	A <sub>dc</sub>
Gate Current—Pulsed	I <sub>GM</sub>	±1.5				A <sub>dc</sub>
Total Power Dissipation @ T <sub>C</sub> =25°C Derate above 25°C	P <sub>D</sub>	40 0.32				Watts W/°C
Operating and Storage Junction Temperature Rangy	T <sub>J</sub> , T <sub>stg</sub>	-55 to 150				°C
Maximum Lead Temp. for Soldering Purposes, 1/8" from case for 5 seconds	T <sub>L</sub>	300				°C

- Notes: (1) T<sub>J</sub>=25°C to 150°C  
 (2) Pulse test: Pulse width≤300μs, Duty Cycle≤2%  
 (3) Repetitive rating: Pulse width limited by max. junction temperature

IRF9220/9221/9222/9223  
 IRFP9220/9221/9222/9223  
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ELECTRICAL CHARACTERISTICS (T<sub>C</sub>=25°C unless otherwise specified)

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Characteristic	Symbol	Type	Min	Typ	Max	Units	Test Conditions
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	IRF9220/2 IRFP9220/2 IRF9620/2	-200	—	—	V	V <sub>GS</sub> =0V
		IRF9221/3 IRFP9221/3 IRF9621/3	-150	—	—	V	I <sub>D</sub> =-250μA
Gate Threshold Voltage	V <sub>GS(th)</sub>	ALL	-2.0	—	-4.0	V	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =-250μA
Gate-Source Leakage Forward	I <sub>GSS</sub>	ALL	—	—	-100	nA	V <sub>GS</sub> =-20V
Gate-Source Leakage Reverse	I <sub>GSS</sub>	ALL	—	—	100	nA	V <sub>GS</sub> =20V
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	ALL	—	—	-250	μA	V <sub>DS</sub> =Max. Rating, V <sub>GS</sub> =0V
		ALL	—	—	-1000	μA	V <sub>DS</sub> =Max. Rating×0.8, V <sub>GS</sub> =0V, T <sub>C</sub> =125°C
On-State Drain-Source Current (2)	I <sub>D(on)</sub>	IRF9220/1 IRFP9220/1 IRF9620/1	-3.5	—	—	A	V <sub>DS</sub> >I <sub>D(on)</sub> ×R <sub>DS(on)</sub> max., V <sub>GS</sub> =-10V
		IRF9222/3 IRFP9222/3 IRF9622/3	-3.0	—	—	A	
Static Drain-Source On-State Resistance (2)	R <sub>DS(on)</sub>	IRF9220/1 IRFP9220/1 IRF9620/1	—	—	1.5	Ω	V <sub>GS</sub> =-10V, I <sub>D</sub> =-1.5A
		IRF9222/3 IRFP9222/3 IRF9622/3	—	—	2.4	Ω	
Forward Transconductance (2)	g <sub>fs</sub>	ALL	1.0	—	—	S	V <sub>DS</sub> >I <sub>D(on)</sub> ×R <sub>DS(on)</sub> max., I <sub>D</sub> =-1.5A
Input Capacitance	C <sub>iss</sub>	ALL	—	—	400	pF	V <sub>GS</sub> =0V, V <sub>DS</sub> =-25V, f=1.0MHz
Output Capacitance	C <sub>oss</sub>	ALL	—	—	125	pF	
Reverse Transfer Capacitance	C <sub>rss</sub>	ALL	—	—	45	pF	
Turn-On Delay Time	t <sub>d(on)</sub>	ALL	—	—	40	ns	V <sub>DD</sub> =0.5BV <sub>DSS</sub> , I <sub>D</sub> =-1.5A, Z <sub>O</sub> =50Ω, (MOSFET switching times are essentially independent of operating temperature.)
Rise Time	t <sub>r</sub>	ALL	—	—	50	ns	
Turn-Off Delay Time	t <sub>d(off)</sub>	ALL	—	—	50	ns	
Fall Time	t <sub>f</sub>	ALL	—	—	40	ns	
Total Gate Charge (Gate-Source Plus Gate-Drain)	Q <sub>g</sub>	ALL	—	—	22	nC	V <sub>GS</sub> =-15V, I <sub>D</sub> =-4.0A, V <sub>DS</sub> =0.8 Max. Rating (Gate charge is essentially independent of operating temperature.)
Gate-Source Charge	Q <sub>gs</sub>	ALL	—	—	9	nC	
Gate-Drain ("Miller") Charge	Q <sub>gd</sub>	ALL	—	—	13	nC	

THERMAL RESISTANCE

Junction-to-Case	R <sub>thJC</sub>	ALL	—	—	3.12	K/W	
Case-to-Sink	R <sub>thCS</sub>	ALL	—	1.0	—	K/W	Mounting surface flat, smooth, and greased
Junction-to-Ambient	R <sub>thJA</sub>	IRFPXXXX IRF96XX	—	—	80	K/W	Free Air Operation
		IRF92XX	—	—	30	K/W	

- Notes: (1) T<sub>J</sub>=25°C to 150°C  
 (2) Pulse test: Pulse width≤300μs, Duty Cycle≤2%  
 (3) Repetitive rating: Pulse width limited by max. junction temperature

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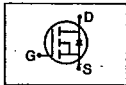
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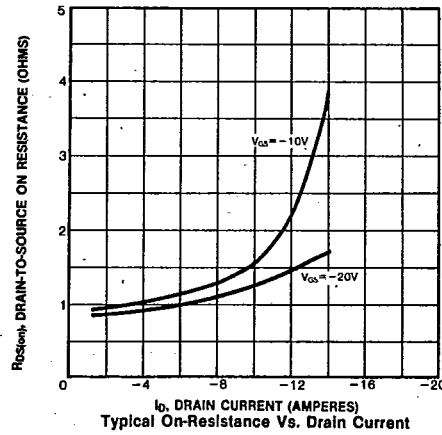
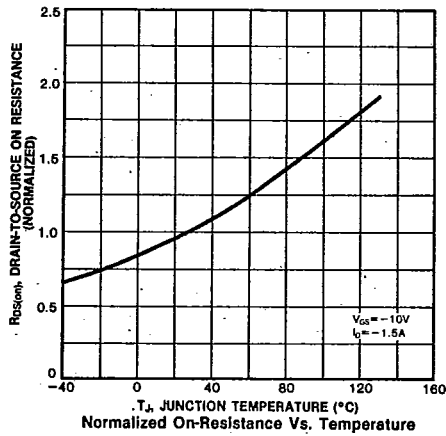
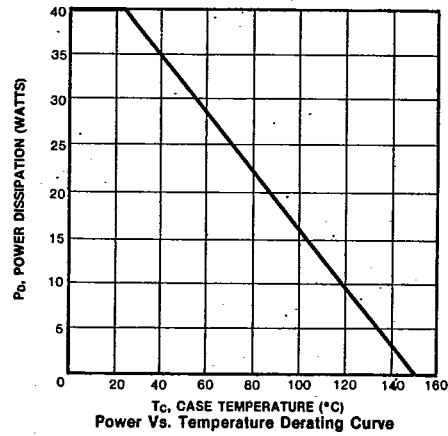
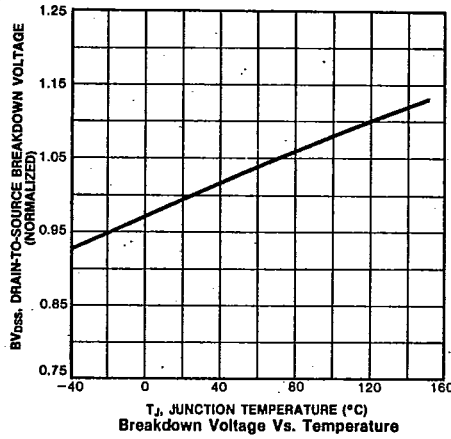
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**SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS**

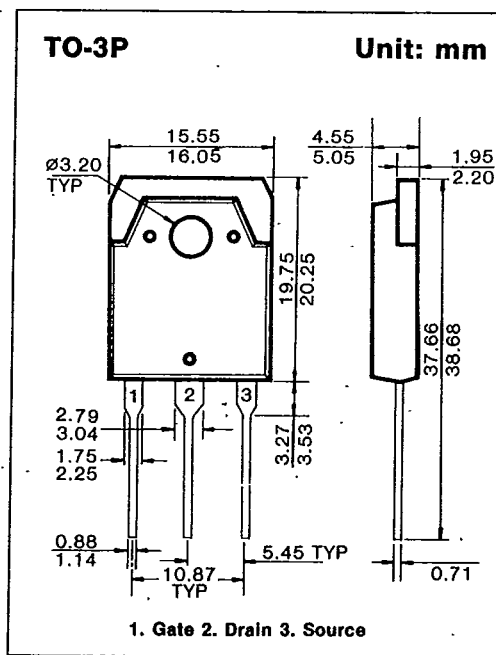
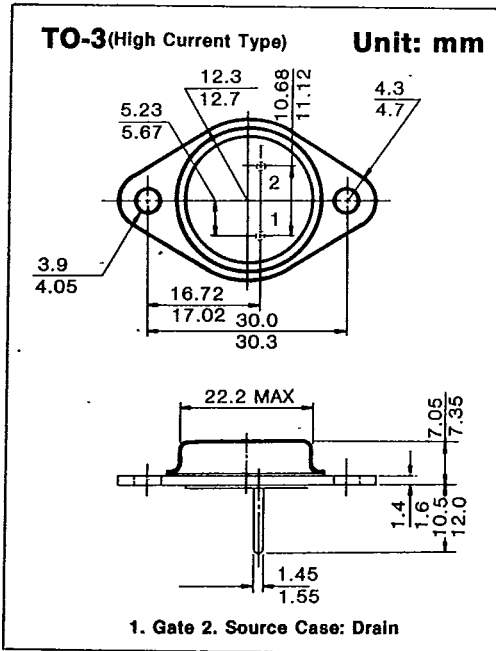
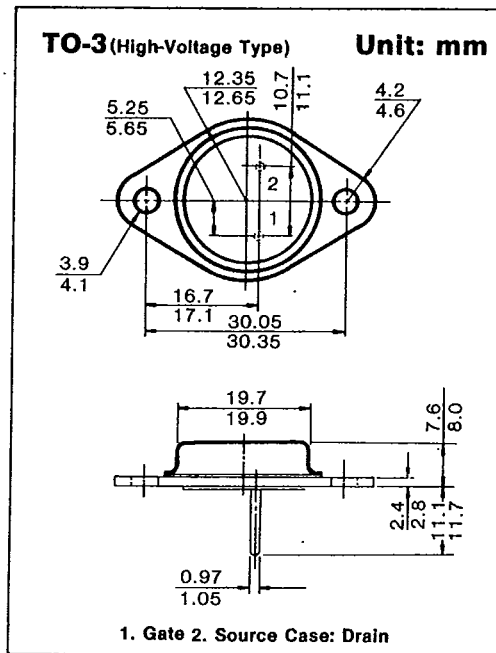
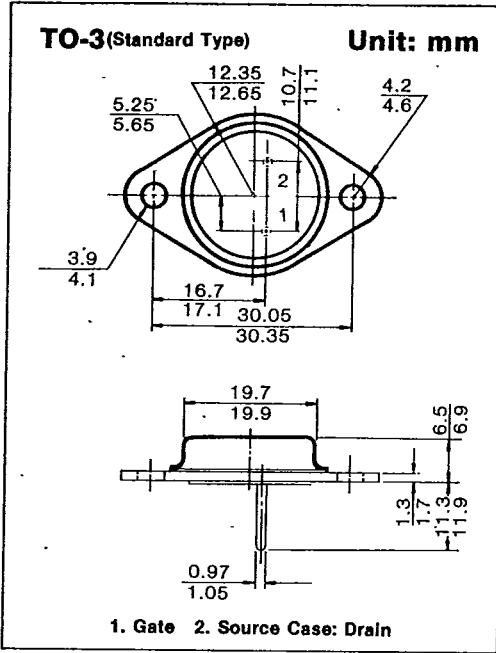
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Characteristic	Symbol	Type	Min	Typ	Max	Units	Test Conditions
Continuous Source Current (Body Diode)	$I_S$	IRF9220/1 IRFP9220/1 IRF9620/1	—	—	-3.5	A	Modified MOSFET symbol showing the integral reverse P-N junction rectifier 
		IRF9232/3 IRFP9232/3 IRF9622/3	—	—	-3.0	A	
Pulse Source Current (Body Diode) (3)	$I_{SM}$	IRF9220/1 IRFP9220/1 IRF9620/1	—	—	-14	A	
		IRF9232/3 IRFP9232/3 IRF9622/3	—	—	-12	A	
Diode Forward Voltage (2)	$V_{SD}$	IRF9220/1 IRFP9220/1 IRF9620/1	—	—	-7.0	V	$T_C=25^\circ\text{C}$ , $I_S=-3.5\text{A}$ , $V_{GS}=0\text{V}$
		IRF9232/3 IRFP9232/3 IRF9622/3	—	—	-6.8	V	$T_C=25^\circ\text{C}$ , $I_S=-3.0\text{A}$ , $V_{GS}=0\text{V}$
Reverse Recovery Time	$t_{rr}$	ALL	—	—	—	ns	$T_J=150^\circ\text{C}$ , $I_F=-3.5\text{A}$ , $dI_F/dt=100\text{A}/\mu\text{s}$

Notes: (1)  $T_J=25^\circ\text{C}$  to  $150^\circ\text{C}$  (2) Pulse test: Pulse width  $\leq 300\mu\text{s}$ , Duty Cycle  $\leq 2\%$   
 (3) Repetitive rating: Pulse width limited by max. junction temperature



**PACKAGE DIMENSIONS**



### PACKAGE DIMENSIONS

